

SEMiX<sup>®</sup> 33c

## Trench IGBT Modules

### SEMiX223GD12E4c

#### Features

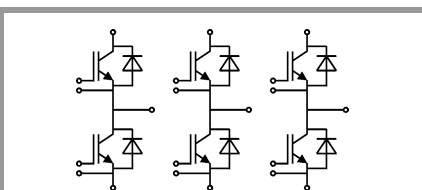
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

#### Typical Applications\*

- AC inverter drives
- UPS
- Electronic Welding

#### Remarks

- Case temperature limited to  $T_C=125^{\circ}\text{C}$  max.
- Product reliability results are valid for  $T_j=150^{\circ}\text{C}$

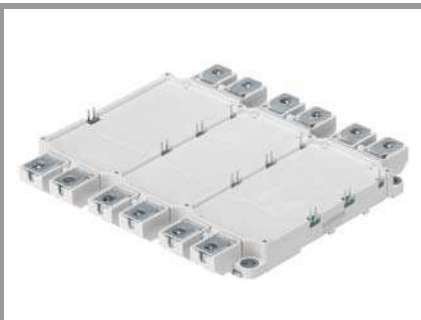


GD

Absolute Maximum Ratings				
Symbol	Conditions	Values	Unit	
<b>IGBT</b>				
$V_{CES}$	$T_j = 25^{\circ}\text{C}$	1200	V	
$I_C$	$T_j = 175^{\circ}\text{C}$	$T_c = 25^{\circ}\text{C}$	333	A
		$T_c = 80^{\circ}\text{C}$	256	A
$I_{Cnom}$		225	A	
$I_{CRM}$	$I_{CRM} = 3 \times I_{Cnom}$	675	A	
$V_{GES}$		-20 ... 20	V	
$t_{psc}$	$V_{CC} = 800\text{ V}$	$T_j = 150^{\circ}\text{C}$	10	$\mu\text{s}$
	$V_{GE} \leq 20\text{ V}$			
	$V_{CES} \leq 1200\text{ V}$			
$T_j$		-40 ... 175	$^{\circ}\text{C}$	
<b>Inverse diode</b>				
$I_F$	$T_j = 175^{\circ}\text{C}$	$T_c = 25^{\circ}\text{C}$	270	A
		$T_c = 80^{\circ}\text{C}$	202	A
$I_{Fnom}$		225	A	
$I_{FRM}$	$I_{FRM} = 3 \times I_{Fnom}$	675	A	
$I_{FSM}$	$t_p = 10\text{ ms, sin } 180^{\circ}, T_j = 25^{\circ}\text{C}$	1161	A	
$T_j$		-40 ... 175	$^{\circ}\text{C}$	
<b>Module</b>				
$I_{t(RMS)}$	$T_{terminal} = 80^{\circ}\text{C}$	600	A	
$T_{stg}$		-40 ... 125	$^{\circ}\text{C}$	
$V_{isol}$	AC sinus 50Hz, $t = 1\text{ min}$	4000	V	

Characteristics					
Symbol	Conditions	min.	typ.	max.	Unit
<b>IGBT</b>					
$V_{CE(sat)}$	$I_C = 225\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^{\circ}\text{C}$	1.85	2.10	V
		$T_j = 150^{\circ}\text{C}$	2.3	2.45	V
$V_{CE0}$	chipelevel	$T_j = 25^{\circ}\text{C}$	0.8	0.9	V
		$T_j = 150^{\circ}\text{C}$	0.7	0.8	V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^{\circ}\text{C}$	4.7	5.3	$\text{m}\Omega$
		$T_j = 150^{\circ}\text{C}$	6.9	7.3	$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C = 9\text{ mA}$	5	5.8	6.5	V
$I_{CES}$	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_j = 25^{\circ}\text{C}$		3.0	$\text{mA}$
		$T_j = 150^{\circ}\text{C}$			$\text{mA}$
$C_{ies}$	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	13.2		$\text{nF}$
$C_{oes}$		$f = 1\text{ MHz}$	0.87		$\text{nF}$
$C_{res}$		$f = 1\text{ MHz}$	0.71		$\text{nF}$
$Q_G$	$V_{GE} = -8\text{ V...} + 15\text{ V}$		1275		$\text{nC}$
$R_{Gint}$	$T_j = 25^{\circ}\text{C}$		3.33		$\Omega$
$t_{d(on)}$	$V_{CC} = 600\text{ V}$ $I_C = 225\text{ A}$	$T_j = 150^{\circ}\text{C}$	213		$\text{ns}$
$t_r$	$V_{GE} = \pm 15\text{ V}$	$T_j = 150^{\circ}\text{C}$	60		$\text{ns}$
$E_{on}$	$R_{Gon} = 1.5\ \Omega$	$T_j = 150^{\circ}\text{C}$	22		$\text{mJ}$
$t_{d(off)}$	$R_{Goff} = 1.5\ \Omega$	$T_j = 150^{\circ}\text{C}$	535		$\text{ns}$
$t_f$	$di/dt_{on} = 3630\text{ A}/\mu\text{s}$ $di/dt_{off} = 2235\text{ A}/\mu\text{s}$	$T_j = 150^{\circ}\text{C}$	113		$\text{ns}$
$E_{off}$		$T_j = 150^{\circ}\text{C}$	31.4		$\text{mJ}$
$R_{th(j-c)}$	per IGBT			0.135	$\text{K/W}$

# SEMiX223GD12E4c



SEMiX® 33c

## Trench IGBT Modules

### SEMiX223GD12E4c

#### Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

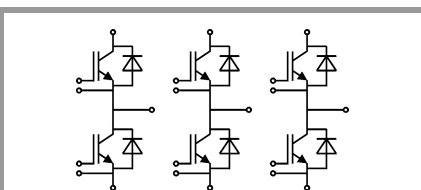
#### Typical Applications\*

- AC inverter drives
- UPS
- Electronic Welding

#### Remarks

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
- Product reliability results are valid for  $T_j=150^\circ\text{C}$

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Inverse diode</b>						
$V_F = V_{EC}$	$I_F = 225\text{ A}$ $V_{GE} = 0\text{ V}$ chiplevel	$T_j = 25^\circ\text{C}$		2.2	2.49	V
		$T_j = 150^\circ\text{C}$		2.1	2.4	V
$V_{F0}$	chiplevel	$T_j = 25^\circ\text{C}$	1.1	1.3	1.5	V
		$T_j = 150^\circ\text{C}$	0.7	0.9	1.1	V
$r_F$	chiplevel	$T_j = 25^\circ\text{C}$	3.6	3.9	4.4	m $\Omega$
		$T_j = 150^\circ\text{C}$	4.7	5.4	5.9	m $\Omega$
$I_{RRM}$	$I_F = 225\text{ A}$	$T_j = 150^\circ\text{C}$		210		A
$Q_{rr}$	$di/dt_{off} = 3900\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		37		$\mu\text{C}$
$E_{rr}$	$V_{GE} = -15\text{ V}$ $V_{CC} = 600\text{ V}$	$T_j = 150^\circ\text{C}$		17.2		mJ
$R_{th(j-c)}$	per diode				0.22	K/W
<b>Module</b>						
$L_{CE}$				20		nH
$R_{CC'+EE'}$	res., terminal-chip	$T_C = 25^\circ\text{C}$		0.7		m $\Omega$
		$T_C = 125^\circ\text{C}$		1		m $\Omega$
$R_{th(c-s)}$	per module			0.014		K/W
$M_s$	to heat sink (M5)		3		5	Nm
$M_t$		to terminals (M6)	2.5		5	Nm
						Nm
$w$					900	g
<b>Temperature Sensor</b>						
$R_{100}$	$T_C=100^\circ\text{C}$ ( $R_{25}=5\text{ k}\Omega$ )			$493 \pm 5\%$		$\Omega$
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$ ; $T[\text{K}]$ ;			$3550 \pm 2\%$		K



GD

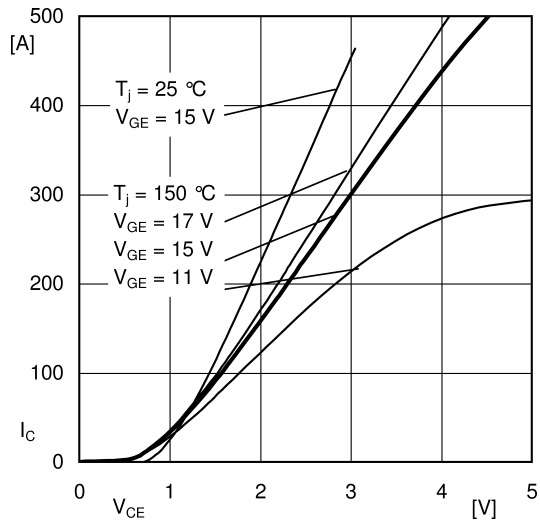


Fig. 1: Typ. output characteristic, inclusive  $R_{CC+EE}$

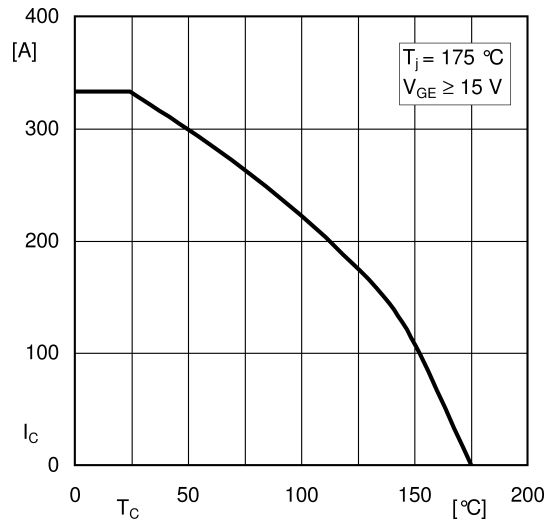


Fig. 2: Rated current vs. temperature  $I_C = f(T_C)$

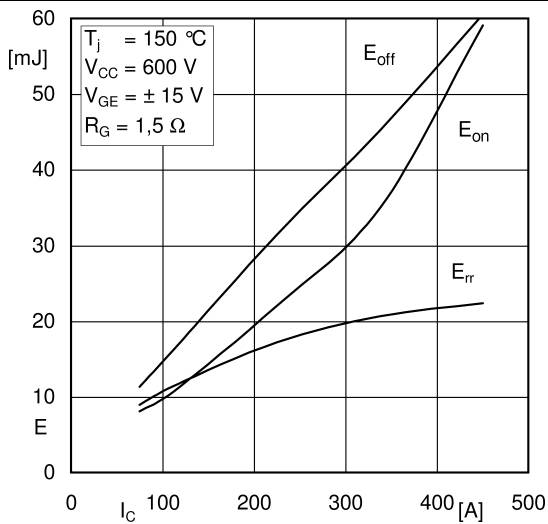


Fig. 3: Typ. turn-on /-off energy =  $f(I_C)$

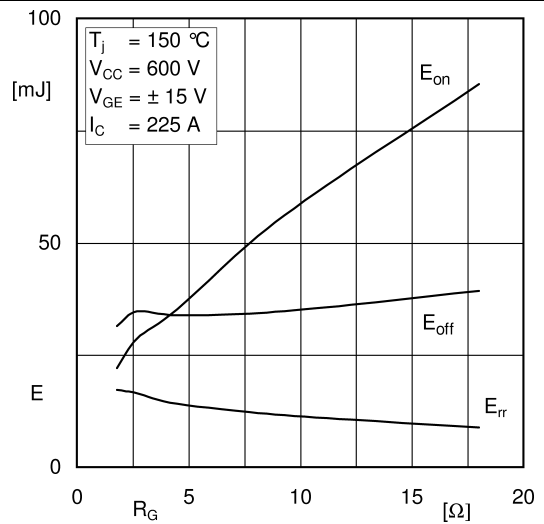


Fig. 4: Typ. turn-on /-off energy =  $f(R_G)$

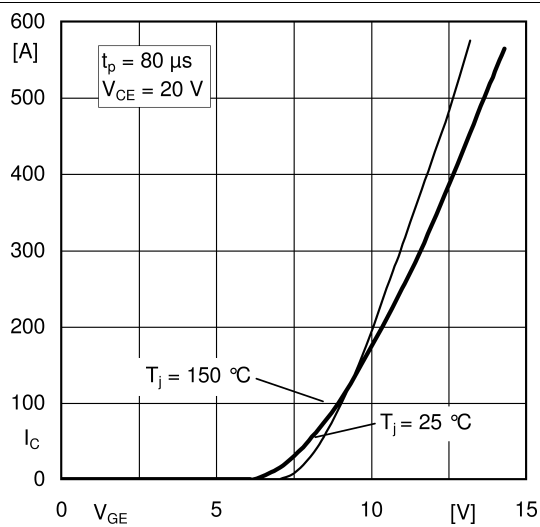


Fig. 5: Typ. transfer characteristic

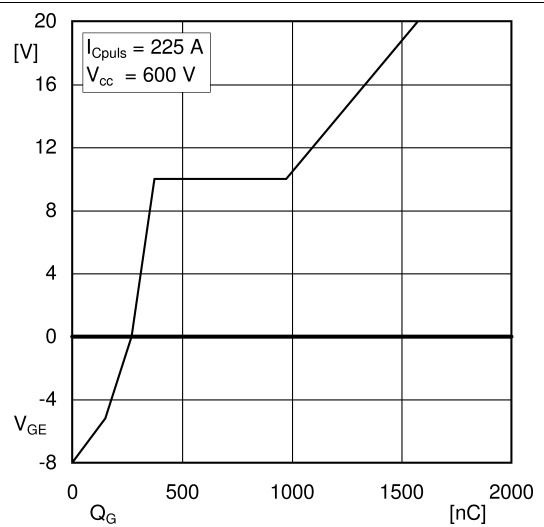


Fig. 6: Typ. gate charge characteristic

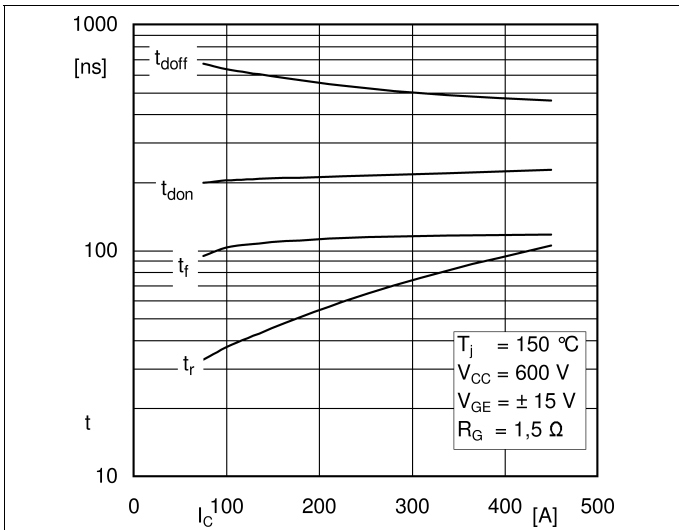


Fig. 7: Typ. switching times vs.  $I_C$

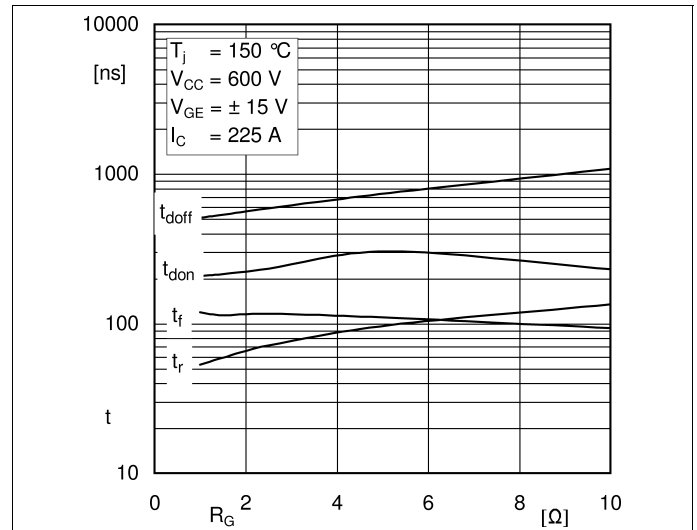


Fig. 8: Typ. switching times vs. gate resistor  $R_G$

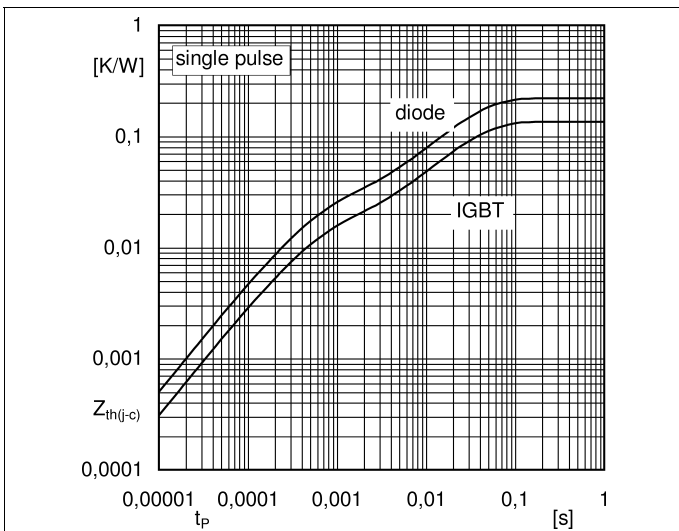


Fig. 9: Typ. transient thermal impedance

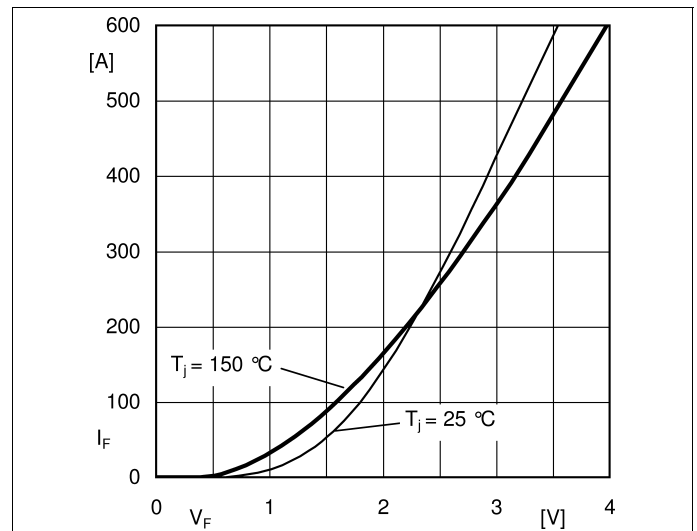


Fig. 10: Typ. CAL diode forward charact., incl.  $R_{CC+EE}$

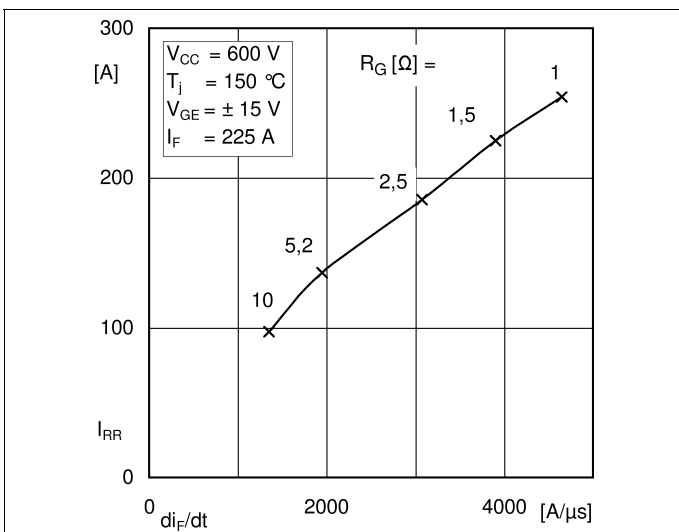


Fig. 11: Typ. CAL diode peak reverse recovery current

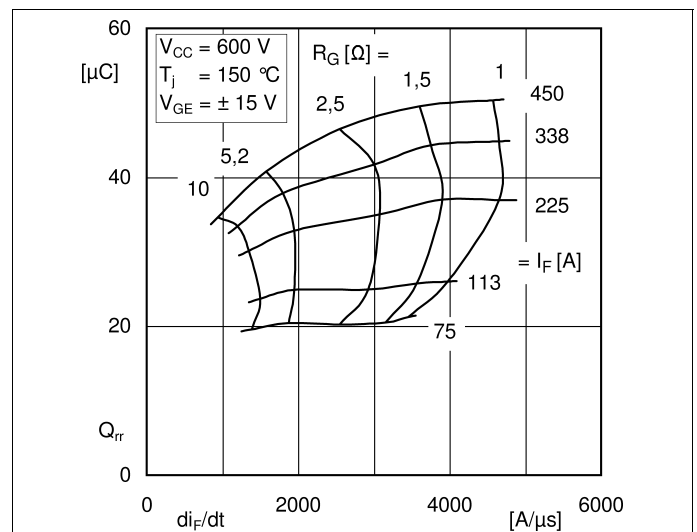


Fig. 12: Typ. CAL diode recovery charge

